

**IN THE SPECIFICATION**

Please replace paragraph beginning at line 8 on page 5 with the following paragraph:

The Figure 1 is a block diagram illustrating a mechanism for enhancing observability of integrated circuit failures during burn-in testing according to one embodiment of the present invention.

Please replace paragraph beginning at line 9 on page 6 with the following paragraph:

Looking now at the Figure 1, a block diagram illustrates a system 10 for enhancing observability of integrated circuit failures during burn-in testing according to one embodiment of the present invention. The system 10 consists of  $n+2$  AND gates (only one AND gate is depicted in the Figure), a configuration register 22 of  $n+2$  width, and a single XOR gate 12. The present inventors alone realized a selection mechanism (sub-system) 11 for individual scan chain 16 and memory built-in self-test (BIST) status 18 outputs to implement this system 10.